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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)			Application Number	10/598,811	
			Filing Date	September 12, 2006	
			First Named Inventor	Christian Pacha	
			Art Unit	N/A	
			Examiner Name	Not Yet Assigned	
Sheet	1	of	1	Attorney Docket Number	V0195.0095

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
/L.N./	AA*	US-20020024368-A1	11-26-2002	Kim	
	AB*	US-6,232,810-B1	05-15-2001	Oklobdzija et al.	
	AC*	US-6,111,444	08-29-2000	Mikan, Jr. et al.	
	AD*	US-6,633,188-B1	10-14-2003	Jia et al.	
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/L.N./	AG*	US-6,107,853	08-22-2000	Nikolic et al.	

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	† <sup>5</sup>
		Country Code <sup>3</sup>	Number*Kind Code <sup>4</sup> (if known)				
/L.N./	BA	JP	2000-299623	10-24-2000	Hitachi Ltd		X

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. \* CITE NO.: Those application(s) which are marked with an single asterisk (\*) next to the Cite No. are not supplied (under 37 CFR 1.98(a)(2)(iii)) because that application was filed after June 30, 2003 or is available in the IFW. \* Applicant's unique citation designation number (optional). \* See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. \* Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). \* For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. \* Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. \* Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T <sup>2</sup>
/L.N./	CA	Markovic, D. et al.; "Analysis and Design of Low-Energy Flip-Flops"; Proceedings of the International Symposium on Low Power Electronics and Design (ISLPED) 2001, Huntington Beach, CA, USA, pages 52-55.			
/L.N./	CB	Dao, H.Q. et al., "Analysis of Clocked Timing Elements for Dynamic Voltage Scaling Effects over Process Parameter Variation"; Proceedings of the International Symposium on Low Power Electronics and Design (ISLPED) 2001, Huntington Beach, CA, USA, pages 56-59.			
/L.N./	CC	Montanaro, J., et al.; "A 160-MHz, 32-b, 0.5-W CMOS RISC Microprocessor"; IEEE Journal of Solid-State Circuits, Vol. 31, No. 11, November 1996, pages 1703-1714.			

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Examiner Signature	/Long Nguyen/	Date Considered	06/22/2009
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